IEC QUALITY ASSESSMENT SYSTEM (IECQ)
covering Electronic Components,
Assemblies, Related Materials and Processes
For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L DEKRA 16.0002-05

CB Certificate No.: DEKRA-T5F-003

Schedule Number: IECQ-L DEKRA 16.0002-05-S **Rev No.:** 1 **Revision Date:** 2025/07/20 **Page** 1 **of** 1

Environmental and Reliability Testing of Electronic Components, Assemblies, and Related Materials

Description test	Standard	Remarks
Consumer / Commercial / Industrial (JESD 47) and Automotive / Electromigration / biased HAST/ Power and Temperature Cycling / Temperature-Humidity with Bias test / High Temperature Operation Life test / Low Temperature Operating Life / Early Life Failure Rate / High Temperature Gate Bias / High Temperature Reverse Bias / Bias Life Test / Pre-SMT / SMT / Solderability	JESD22-A101/A105/A108/110 JESD33/63/87 JEP001/154 IEC 60068-2-1/2/3/38 MIL-STD-750/883 EIAJ ED-4701 AEC-Q100-008 IPC-7525/A-610/B102/J-STD-002	Or customer specified test

DEKRA Certification B.V. Meander 1051, Arnhem. Netherlands